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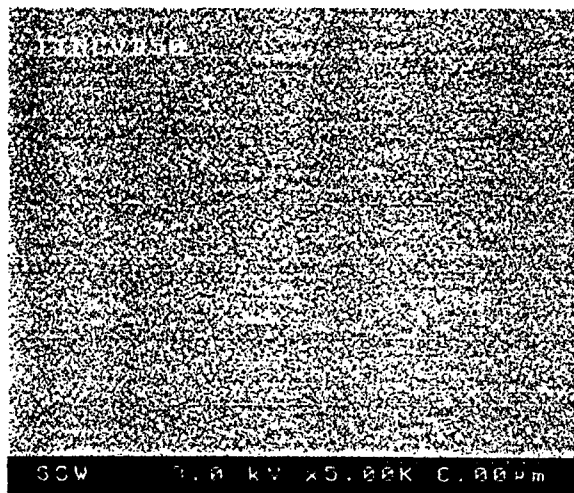


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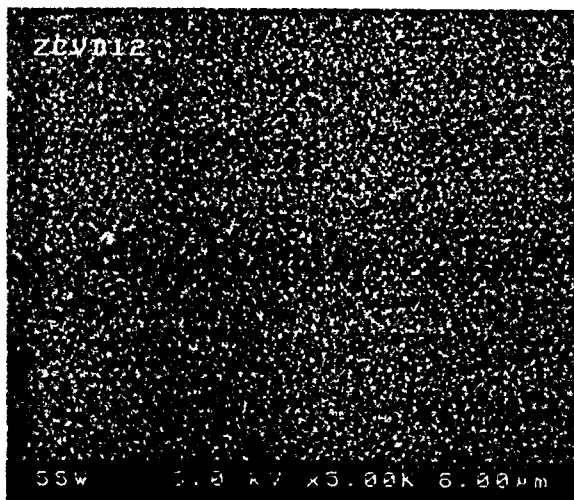
Figure 1. SEM micrographs of yttria (a and b) and zirconia (c and d) films grown on TiN



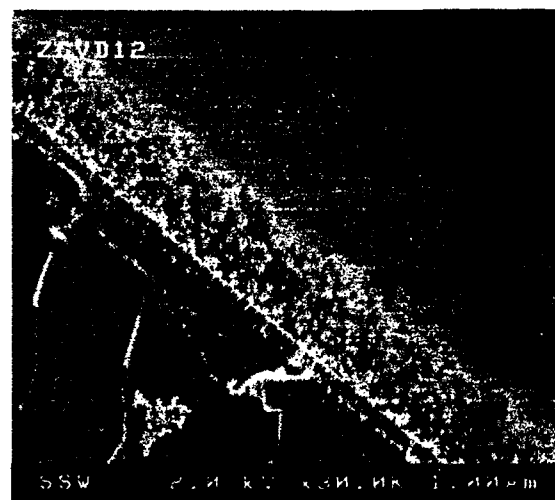
(a)



(b)



(c)



(d)

Figure 2 Relationship between amount of carbon impurity and palladium metal (in atomic percentage) in the Co/Pd thin film.

